

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 247976US2S DIV		SERIAL NO. NEW APPLICATION	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fumio HORIGUCHI			
				FILING DATE HEREWITH		GROUP UNASSIGNED	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>[initials]</i>	AA	4,419,743	12/6/83	Masao TAGUCHI et al.			
<i>[initials]</i>	AB	4,979,014	12/18/90	Katsuhiko HIEDA et al.			
<i>[initials]</i>	AC	5,258,635	11/02/93	Akihiro NITAYAMA et al.			
<i>[initials]</i>	AD	5,250,830	10/05/93	Atushi YAGISHITA et al.			
<i>[initials]</i>	AE	5,350,708	9/27/94	Atsushi YAGISHITA et al.			
<i>[initials]</i>	AF	5,736,761	4/7/98	Lothar RISCH et al.			
<i>[initials]</i>	AG	6,172,391	1/2001	GOEBEL et al.			
<i>[initials]</i>	AH	6,075,265	7/2000	GOEBEL et al.			
<i>[initials]</i>	AI	5,977,589	11/1999	Schloesser et al.			
<i>[initials]</i>	AJ	5,504,357	4/1996	KIM et al.			
<i>[initials]</i>	AK	6,355,954	3/2002	GALL et al.			
<i>[initials]</i>	AL	6,593,613	7/2003	ALSMIEIER et al.			
<i>[initials]</i>	AM						
<i>[initials]</i>	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
<i>[initials]</i>	AO	62-155557	7/10/87	Japan		X	
<i>[initials]</i>	AP	2519216	5/17/96	Japan		X	
<i>[initials]</i>	AQ	8-330545	12/13/96	Japan		X	
<i>[initials]</i>	AR	8-34302	3/29/96	Japan		X	
<i>[initials]</i>	AS	57-23261	2/6/82	Japan		X	
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>[initials]</i>	AW	Masao TAGUCHI et al., "A Capacitance-Coupled Bit-Line Cell for Mb Level DRAMs," ISSCC 84, February 22, 1984, pgs. 100-101					
	AX						
	AY						
	AZ						
					<input type="checkbox"/> Additional References sheet(s) attached		
Examiner J. MONDT <i>[signature]</i>					Date Considered 02/27/05		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							